Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
Ц	1276	Scanning adj electron adj microscope?	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 14:05
L2	25492	Scanning adj electron adj microscope	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 14:06
L3	287	2 and ( lens near4 wafer )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 14:07
L4	17	3 and ( retarding near4 voltage )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 14:53
L5	21	3 and ( automatic near4 focus\$3 )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 14:40
L6	3	3 and ( movable near4 holder )	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	AND	ON	2004/12/27 15:10
L7	2370	((250/307,310,397,) or (345/771, )).CCLS.	USPAT	OR	OFF	2004/12/27 15:11
L8	604	7 and SEM	USPAT	OR	OFF	2004/12/27 15:12
L9	35	8 and ( lens near4 wafer )	USPAT	OR	OFF	2004/12/27 15:12
L10	4	9 and ( retarding near4 voltage )	USPAT	OR	OFF	2004/12/27 15:13